

INTERNATIONAL STANDARD



**Semiconductor devices –
Part 5-10: Optoelectronic devices – Light emitting diodes – Test method of the
internal quantum efficiency based on the room-temperature reference point**



THIS PUBLICATION IS COPYRIGHT PROTECTED

Copyright © 2019 IEC, Geneva, Switzerland

All rights reserved. Unless otherwise specified, no part of this publication may be reproduced or utilized in any form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from either IEC or IEC's member National Committee in the country of the requester. If you have any questions about IEC copyright or have an enquiry about obtaining additional rights to this publication, please contact the address below or your local IEC member National Committee for further information.

IEC Central Office
3, rue de Varembe
CH-1211 Geneva 20
Switzerland

Tel.: +41 22 919 02 11
info@iec.ch
www.iec.ch

About the IEC

The International Electrotechnical Commission (IEC) is the leading global organization that prepares and publishes International Standards for all electrical, electronic and related technologies.

About IEC publications

The technical content of IEC publications is kept under constant review by the IEC. Please make sure that you have the latest edition, a corrigendum or an amendment might have been published.

IEC publications search - webstore.iec.ch/advsearchform

The advanced search enables to find IEC publications by a variety of criteria (reference number, text, technical committee,...). It also gives information on projects, replaced and withdrawn publications.

IEC Just Published - webstore.iec.ch/justpublished

Stay up to date on all new IEC publications. Just Published details all new publications released. Available online and once a month by email.

IEC Customer Service Centre - webstore.iec.ch/csc

If you wish to give us your feedback on this publication or need further assistance, please contact the Customer Service Centre: sales@iec.ch.

Electropedia - www.electropedia.org

The world's leading online dictionary on electrotechnology, containing more than 22 000 terminological entries in English and French, with equivalent terms in 16 additional languages. Also known as the International Electrotechnical Vocabulary (IEV) online.

IEC Glossary - std.iec.ch/glossary

67 000 electrotechnical terminology entries in English and French extracted from the Terms and Definitions clause of IEC publications issued since 2002. Some entries have been collected from earlier publications of IEC TC 37, 77, 86 and CISPR.

Preview generated by EVS

INTERNATIONAL STANDARD



**Semiconductor devices –
Part 5-10: Optoelectronic devices – Light emitting diodes – Test method of the
internal quantum efficiency based on the room-temperature reference point**

INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

ICS 31.080.99

ISBN 978-2-8322-7655-6

Warning! Make sure that you obtained this publication from an authorized distributor.

CONTENTS

| | |
|--|----|
| FOREWORD..... | 3 |
| 1 Scope..... | 5 |
| 2 Normative references | 5 |
| 3 Terms, definitions and abbreviated terms | 5 |
| 3.1 Terms and definitions..... | 5 |
| 3.2 Abbreviated terms..... | 7 |
| 4 Measuring methods | 7 |
| 4.1 Basic requirements | 7 |
| 4.1.1 Measuring conditions..... | 7 |
| 4.1.2 Measuring instruments and equipment..... | 8 |
| 4.2 Purpose | 8 |
| 4.3 Measurement..... | 8 |
| 4.3.1 Measurement setup | 8 |
| 4.3.2 Measurement principle..... | 8 |
| 4.3.3 Measurement sequence..... | 8 |
| 5 Test report..... | 10 |
| Annex A (informative) Test example..... | 11 |
| Bibliography..... | 16 |
| | |
| Figure 1 – Test flow | 10 |
| Figure A.1 – Radiant power as a function of forward current | 11 |
| Figure A.2 – Relative EQE as a function of forward current..... | 12 |
| Figure A.3 – Determination of peak EQE point in the relative EQE curve | 12 |
| Figure A.4 – Conversion to the normalized variables of X and Y | 13 |
| Figure A.5 – Coefficients a_1 and a_2 as a function of X | 13 |
| Figure A.6 – Verification of a reference point in the a_2 curve..... | 14 |
| Figure A.7 – IQE as a function of forward current..... | 14 |
| | |
| Table A.1 – Summary of test report..... | 15 |

INTERNATIONAL ELECTROTECHNICAL COMMISSION

SEMICONDUCTOR DEVICES –

**Part 5-10: Optoelectronic devices – Light emitting diodes –
Test method of the internal quantum efficiency based on
the room-temperature reference point**

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
- 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
- 4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter.
- 5) IEC itself does not provide any attestation of conformity. Independent certification bodies provide conformity assessment services and, in some areas, access to IEC marks of conformity. IEC is not responsible for any services carried out by independent certification bodies.
- 6) All users should ensure that they have the latest edition of this publication.
- 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
- 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
- 9) Attention is drawn to the possibility that some of the elements of this IEC Publication may be the subject of patent rights. IEC shall not be held responsible for identifying any or all such patent rights.

International Standard IEC 60747-5-10 has been prepared by subcommittee 47E: Discrete semiconductor devices, of IEC technical committee 47: Semiconductor devices.

The text of this International Standard is based on the following documents:

| | |
|-------------|------------------|
| CDV | Report on voting |
| 47E/652/CDV | 47E/677/RVC |

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 60747 series, published under the general title *Semiconductor devices*, can be found on the IEC website.

Future standards in this series will carry the new general title as cited above. Titles of existing standards in this series will be updated at the time of the next edition.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

IMPORTANT – The 'colour inside' logo on the cover page of this publication indicates that it contains colours which are considered to be useful for the correct understanding of its contents. Users should therefore print this document using a colour printer.

SEMICONDUCTOR DEVICES –

Part 5-10: Optoelectronic devices – Light emitting diodes – Test method of the internal quantum efficiency based on the room-temperature reference point

1 Scope

This part of IEC 60747 specifies the measuring method of the internal quantum efficiency (IQE) of single light emitting diode (LED) chips or packages without phosphor. White LEDs for lighting applications are out of the scope of this document. This document utilizes only the relative external quantum efficiency (EQE) measured at an operating room temperature. In order to identify the reference IQE, an operating current corresponding to the injection efficiency of 100 % is found and the radiative efficiency is determined by the infinitesimal change of the relative EQE at that point. The IQE as a function of current is then calculated from the relative ratio of the EQEs to the value at the reference point, which is called room-temperature reference-point method (RTRM).

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60747-5-6:2016, *Semiconductor devices – Part 5-6: Optoelectronic devices – Light emitting diodes*

3 Terms, definitions and abbreviated terms

3.1 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>

3.1.1

internal quantum efficiency

η_{IQE}

ratio of the number of photons emitted from the active region per unit time to the number of electrons injected into the LED per unit time

$$\eta_{IQE} = \frac{\Phi_{e,active} / h\bar{\nu}}{I_F / q}$$

where

$\Phi_{e,active}$ is the radiant power emitted from the active region

$h\bar{\nu}$ is the mean photon energy

I_F is the forward current

q is the elementary charge